

March 1988 Revised August 1999

74F841 10-Bit Transparent Latch

General Description

The 74F841 bus interface latch is designed to eliminate the extra packages required to buffer existing latches and provide extra data width for wider address/data paths or buses carrying parity. The 74F841 is a 10-bit transparent latch, a 10-bit version of the 74F373.

Features

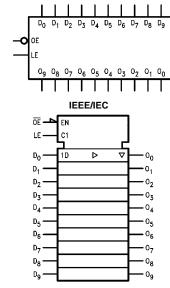
■ 3-STATE output

Ordering Code:

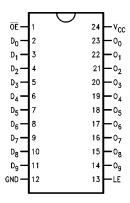
Order Number	Package Number	Package Description
74F841SC	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F841SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbols



Connection Diagram



Unit Loading/Fan Out

Pin Names	Description	U.L.	Input I _{IH} /I _{IL}	
Pin Names	Description	HIGH/LOW	Output I _{OH} /I _{OL}	
D ₀ –D ₉	Data Inputs	1.0/1.0	20 μA/-0.6 mA	
O ₀ –O ₉	3-STATE Outputs	150/40	−3 mA/24 mA	
ŌĒ	Output Enable Input	1.0/1.0	20 μA/-0.6 mA	
LE	Latch Enable	1.0/1.0	20 μA/-0.6 mA	

Functional Description

The 74F841 device consists of ten D-type latches with 3-STATE outputs. The flip-flops appear transparent to the data when Latch Enable (LE) is HIGH. This allows asynchronous operation, as the output transition follows the data in transition.

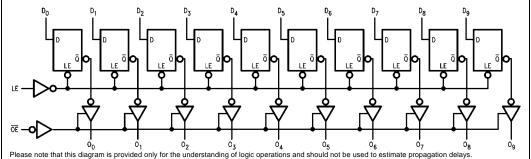
On the LE HIGH-to-LOW transition, the data that meets the setup and hold time is latched. Data appears on the bus when the Output Enable $(\overline{\text{OE}})$ is LOW. When $\overline{\text{OE}}$ is HIGH the bus output is in the high impedance state.

Function Table

ı	Inputs		Internal	Output	Function	
OE	LE	D	Q	0	Function	
Χ	Х	Χ	Х	Z	High Z	
Н	Н	L	L	Z	High Z	
Н	Н	Н	Н	Z	High Z	
Н	L	Χ	NC	Z	Latched	
L	Н	L	L	L	Transparent	
L	Н	Н	Н	Н	Transparent	
L	L	Χ	NC	NC	Latched	
L	Χ	Χ	Н	Н	Preset	
L	Χ	Χ	L	L	Clear	
L	Χ	Χ	Н	Н	Preset	
Н	L	Χ	L	Z	Latched	
Н	L	Χ	Н	Z	Latched	

H = HIGH Voltage Level

Logic Diagram



L = LOW Voltage Level X = Immaterial

X = Immaterial Z = HIGH Impedance

NC = No Change

Absolute Maximum Ratings(Note 1)

-65°C to +150°C Storage Temperature Ambient Temperature under Bias -55°C to +125°C

Junction Temperature under Bias -55°C to +150°C V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with $V_{CC} = 0V$)

Standard Output -0.5V to V_{CC}

3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA)

Recommended Operating Conditions

Free Air Ambient Temperature 0°C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

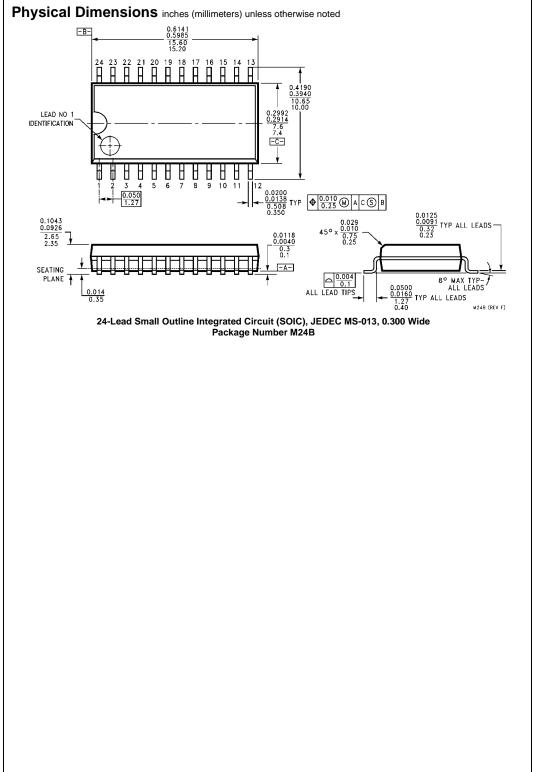
Symbol	ol Parameter		rameter Min Typ		Max	Units	v _{cc}	Conditions	
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal	
V _{IL}	Input LOW Voltage				8.0	V		Recognized as a LOW Signal	
V _{CD}	Input Clamp Diode Voltage				-1.2	V	Min	I _{IN} = -18 mA	
V _{OH}	Output HIGH Voltage	10% V _{CC}	2.5					I _{OH} = -1 mA	
		10% V _{CC}	2.4			V	Min	$I_{OH} = -3 \text{ mA}$	
		5% V _{CC}	2.7			V		I _{OH} = -1 mA	
		5% V _{CC}	2.7					$I_{OH} = -3 \text{ mA}$	
V _{OL}	Output LOW Voltage	10% V _{CC}			0.5	V	Min	I _{OL} = 24 mA	
I _{IH}	Input HIGH Current				5.0	μА	Max	V _{IN} = 2.7V	
I _{BVI}	Input HIGH Current Breakdown Test				7.0	μΑ	Max	V _{IN} = 7.0V	
I _{CEX}	Output HIGH Leakage Current				50	μА	Max	$V_{OUT} = V_{CC}$	
V _{ID}	Input Leakage Test		4.75			V	0.0	I _{ID} = 1.9 μA All Other Pins Grounded	
I _{OD}	Output Leakage Circuit Current				3.75	μА	0.0	V _{IOD} = 150 mV All Other Pins Grounded	
I _{IL}	Input LOW Current				-0.6	mA	Max	V _{IN} = 0.5V	
l _{ozh}	Output Leakage Current				50	μΑ	Max	V _{OUT} = 2.7V	
l _{OZL}	Output Leakage Current				-50	μΑ	Max	V _{OUT} = 0.5V	
Ios	Output Short-Circuit Current		-60		-150	mA	Max	V _{OUT} = 0V	
I _{ZZ}	Bus Drainage Test				500	μΑ	0.0V	V _{OUT} = 5.25V	
I _{CCZ}	Power Supply Current			69	92	mA	Max	V _O = HIGH Z	

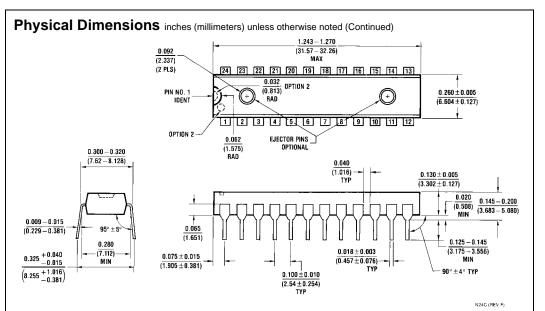
AC Electrical Characteristics

Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_{A} = 0^{\circ}C \text{ to } +70^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$		Units	
		Min	Тур	Max	Min	Max		
t _{PLH}	Propagation Delay	2.5		8.0	2.0	9.0	no	
t _{PHL}	D _n to O _n	1.5		6.5	1.5	7.0	ns	
t _{PLH}	Propagation Delay	5.0		12.0	4.5	13.5	no	
t _{PHL}	LE to O _n	2.0		7.5	2.0	8.0	ns	
t _{PZH}	Output Enable Time	2.5		8.5	2.0	9.5		
t_{PZL}	OE to O _n	2.5		9.0	2.0	10.0		
t _{PHZ}	Output Disable Time	1.0		6.5	1.0	7.5	ns	
t _{PLZ}	OE to O _n	1.0		6.5	1.0	7.5		

AC Operating Requirements

Symbol	Parameter		$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$	
		Min	Max	Min	Max	
t _S (H)	Setup Time, HIGH or LOW	2.0		2.5		
t _S (L)	D _n to LE	2.0		2.5		ns
t _H (H)	Hold Time, HIGH or LOW	2.5		3.0		115
t _H (L)	D _n to LE	3.0		3.5		
t _W (H)	LE Pulse Width, HIGH	4.0		4.0		ns





24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300 Wide Package Number N24C

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